

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.010106.6		APPLICATION NO. <u>10/776171</u> NOT YET ASSIGNED	
				APPLICANT TOSHIKAZU OHNISHI ET AL.			
				FILING DATE FILED HEREWITH		GROUP 2879	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JW</i>		6,348,761 B1	2/02	Nomura et al.	313	495	6/94
<i>JW</i>		4,949,019	8/90	Isaka et al.	445	6	
<i>JW</i>		5,066,883	11/91	Yoshioka et al.	313	309	
<i>JW</i>		5,006,883	11/91	Yoshioka et al.	313	309	
<i>JW</i>		4,954,744	9/90	Suzuki et al.	313	336X	
<i>JW</i>		5,285,129	2/94	Takeda et al.	313	309X,	
<i>JW</i>		5,256,936	10/93	Itoh et al.	313	309X	
<i>JW</i>		5,141,460	8/92	Jaskie et al.	313	309X	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
<i>JW</i>		0523702A1	1/93	EPO	_____	_____	Abstract
<i>JW</i>		1283749A	11/89	JAPAN	_____	_____	Abstract
<i>JW</i>		A1309242	12/89	JAPAN	_____	_____	No
<i>JW</i>		536731A1	4/93	EPO	_____	_____	
<i>JW</i>		1-309242	12/89	JAPAN	_____	_____	Translation
<i>JW</i>		0 299 461	1/89	EPO	_____	_____	
EXAMINER <i>Joseph William</i>				DATE CONSIDERED <u>12/7/04</u>			

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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		
		"Metal Influence on Switching MIM Diodes", H. Pagnia, et al., Phys. Stat. Sol. (a), 111, 387 (1989) no month
		"Scanning Tunnelling Microscopic Investigations of Electroformed Planar Metal-Insulator-Metal Diodes," H. Pagnia, N. Sotnik and W. Wirth, Int. J. Electronics, Vol. 69, No. 1, 25-32 (1990) no month
		"Energy Distribution of Emitted Electrons from Electroformed MIM Structures: The Carbon Island Model," M. Bischoff, H. Pagnia and J. Trickl, Int. J. Electronics, Vol. 73, No. 5, 1009-1010 (1992) no month
		"Thin Film Handbook," Committee 131 of Japanese Society for the Promotion of Art and Science no month
		"On the Electron Emission from Evaporated Thin Au Films," M. Bischoff, R. Holzer and H. Pagnia, Physics Letters, Vol. 62A, No. 7 (October 3, 1977)
		"The Electroforming Process in MIM Diodes," Vol. 85, R. Blessing, H. Pagnia and N. Sotnik, Thin Solid Films, 119-128 (1981)
		"Evidence for the Contribution of an Adsorbate to the Voltage-Controlled Negative Resistance of Gold Island Film Diodes," R. Blessing, H. Pagnia and R. Schmitt, Thin Solid Films, Vol. 78, 397-401 (1981)
		"Water-Influenced Switching in Discontinuous Au Film Diodes," R. Muller and H. Pagnia, Materials Letters, Vol. 2, No. 4A, 283-285 (March 1984)
		"Influence of Organic Molecules on the Current-Voltage Characteristic of Planar MIM Diodes," H. Pagnia, N. Sotnik and H. Strauss, Phy. Stat. Sol., Vol. 90, 771-778 (1985)
		"Influence of Gas Composition on Regeneration in Metal/Insulator/Metal Diodes," M. Borbonus, H. Pagnia and N. Sotnik, Thin Solid Films, Vol. 151, 333-342 (1987)
		"Prospects for Metal/Non-Metal Microsystems: Sensors, Sources and Switches," H. Pagnia, Int. J. Electronics, Vol. 73, No. 5, 319-825 (1992)
		W.P. Dyke, et al., "Field Emission," Advances in Electronics and Electron Physics, 1956, pp. 90-185 no month
		C.A. Spindt, et al. "Physical Properties of Thin-Film Field Emission Cathodes With Molybdenum Cones," J. Appl. Phys., Vol. 47 (1976) pp. 5248-5263 no month
		C.A. Mead, "Operation of Tunnel-Emission Devices," J. Appl. Phys., Vol. 32, (1961) pp. 646-652 no month
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<i>QW</i>		M.I. Elinson "The Emission of Hot Electrons and the Field Emission of Electrons from Tin Oxide," Radio Engineering and Electronic Physics, (1965), pp. 1290-1296 <i>no month</i>	
<i>QW</i>		G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films," Thin Solid Films, 9, (1972) pp. 317-328 <i>no month</i>	
<i>QW</i>		H. Hartwell, et al, "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films," Int'l Electron Devices Meeting (1975) pp. 519-521 <i>no month</i>	
<i>QW</i>		M. Araki, "Electroforming and Electron Emission of Carbon Thin Films," J. Vac. Soc. Japan, 26, (1983) pp. 22-29 <i>no month</i>	
<i>QW</i>		"Carbon-Nanoslit Model for the Electroforming Process in MIM Structures," M. Bischoff, Int. J. Electronics, Vol. 70, No. 3, 491-498 (1991) <i>no month</i>	
<i>QW</i>		Patent Abstracts of Japan, vol. 14, no. 1 08 (E-896) (4051), Feb 27, 1990	
EXAMINER <i>Joseph W. Allen</i>		DATE CONSIDERED <u>12/7/04</u>	

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U.S. PATENT DOCUMENTS						
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<i>AN</i>	6,147,449	11/14/00	Iwasaki et al.	313	495	
<i>AN</i>	6,171,162 B1	01/09/01	Iwasaki et al.	445	6	
<i>AN</i>	6,169,356 B1	01/02/01	Ohnishi et al.	313	495	
<i>AN</i>	6,184,610 B1	02/06/01	Shibata et al.	313	309	
<i>AN</i>	6,246,168 B1	06/12/01	Kishi et al.	313	495	
<i>AN</i>	6,384,541 B1	05/07/02	Ohnishi et al.	315	169.3	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
<i>AN</i>	1069826 A	3/10/93	China	H01J	1/30	Abst. & Trans.
<i>AN</i>	1069828 A	3/10/93	China	H01J	19/42	Abst., Trans. & EP 0 513 777
<i>AN</i>	1-031332	02/01/89	Japan	H01J	29/48	Abst.
<i>AN</i>	0 513 777 A2	11/19/92	EPO	H01J	1/30	English
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